MOSFET Power Transistor

BLF348

65V / 25A

DATASHEET

OEM – Philips

Source: Philips Data Handbook SC19a 1998

VHF linear push-pull power MOS transistor BLF348

FEATURES

- High power gain
- Easy power control
- Good thermal stability
- Gold metallization ensures excellent reliability.

DESCRIPTION

Dual push-pull silicon N-channel enhancement mode vertical D-MOS transistor, designed for broadcast transmitter applications in the VHF frequency range.

The transistor is encapsulated in a 4-lead, SOT262 A1 balanced flange envelope, with two ceramic caps. The mounting flange provides the common source connection for the transistors.

PIN CONFIGURATION

Fig.1 Simplified outline and symbol.

CAUTION

The device is supplied in an antistatic package. The gate-source input must be protected against static charge during transport and handling.

PINNING – SOT262A1

PIN	DESCRIPTION
1	drain 1
2	drain 2
3	gate 1
4	gate 2
5	source

WARNING

Product and environment safety - toxic materials

This product contains beryllium oxide. The product is entirely safe provided that the BeO discs are not damaged. All persons who handle, use or dispose of this product should be aware of its nature and of the necessary safety precautions. After use, dispose of as chemical or special waste according to the regulations applying at the location of the user. It must never be thrown out with the general or domestic waste.

QUICK REFERENCE DATA

RF performance in a push-pull common source test circuit.

MODE OF OPERATION	f_{vision} (MHz)	V_{DS} (V)	I_D (A)	T_h (°C)	d_{im} (dB) (note 1)	$P_{o\ sync}$ (W)	G_p (dB)
class-A	224.25	28	2 × 4.6	70	−52	> 67	> 11
	224.25	28	2 × 4.6	25	−52	typ. 75	typ. 13

Note

1. Three-tone test method (vision carrier −8 dB, sound carrier −7 dB, sideband signal −16 dB), zero dB corresponds to peak synchronization level.

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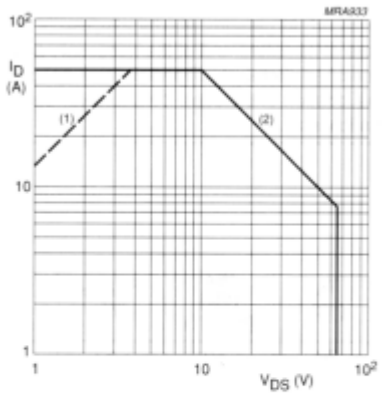
LIMITING VALUES

In accordance with the Absolute Maximum System (IEC 134).
Per transistor section unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V_{DSS}	drain-source voltage		–	65	V
$\pm V_{GSS}$	gate-source voltage		–	20	V
I_D	DC drain current		–	25	A
P_{tot}	total power dissipation	up to T_{mb} = 25 °C; total device; both sections equally loaded	–	500	W
T_{stg}	storage temperature		–65	150	°C
T_j	junction temperature		–	200	°C

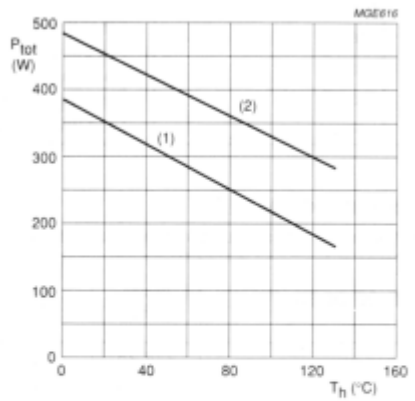
THERMAL RESISTANCE

SYMBOL	PARAMETER	CONDITIONS	THERMAL RESISTANCE
$R_{th\ j\text{-}mb}$	thermal resistance from junction to mounting base	total device; both sections equally loaded	0.35 K/W
$R_{th\ mb\text{-}h}$	thermal resistance from mounting base to heatsink	total device; both sections equally loaded	0.15 K/W



(1) Current is this area may be limited by $R_{DS(on)}$.
(2) T_{mb} = 25 °C.
Total device; both sections equally loaded.

Fig.2 DC SOAR.



(1) Continuous operation.
(2) Short-time operation during mismatch.
Total device; both sections equally loaded.

Fig.3 Power/temperature derating curves.

CHARACTERISTICS (per section)

T_j = 25 °C unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$V_{(BR)DSS}$	drain-source breakdown voltage	V_{GS} = 0; I_D = 0.1 A	65	–	–	V
I_{DSS}	drain-source leakage current	V_{GS} = 0; V_{DS} = 28 V	–	–	5	mA
I_{GSS}	gate-source leakage current	±V_{GS} = 20 V; V_{DS} = 0	–	–	1	µA
$V_{GS(th)}$	gate-source threshold voltage	I_D = 0.1 A; V_{DS} = 10 V	2	–	4.5	V
$\Delta V_{GS(th)}$	gate-source voltage difference of both transistor sections	I_D = 0.1 A; V_{DS} = 10 V	–	–	100	mV
g_{fs}	forward transconductance	I_D = 8 A; V_{DS} = 10 V	5	7.5	–	S
g_{fs1}/g_{fs2}	forward transconductance ratio of both transistor sections	I_D = 8 A; V_{DS} = 10 V	0.9	–	1.1	
$R_{DS(on)}$	drain-source on-state resistance	I_D = 8 A; V_{GS} = 10 V	–	0.1	0.15	Ω
I_{DSX}	on-state drain current	V_{GS} = 10 V; V_{DS} = 10 V	–	37	–	A
C_{is}	input capacitance	V_{GS} = 0; V_{DS} = 28 V; f = 1 MHz	–	495	–	pF
C_{os}	output capacitance	V_{GS} = 0; V_{DS} = 28 V; f = 1 MHz	–	340	–	pF
C_{rs}	feedback capacitance	V_{GS} = 0; V_{DS} = 28 V; f = 1 MHz	–	40	–	pF